

SEM ICAPS

Excellence In Innovation

Localize and Characterize Metal and Junction Defects !

SEM ICAPS Scanning Optical Microscope System

An integrated compucentric Scanning Optical Microscope System, designed for maximum ease of use and flexibility. The system is optimized for maximum sensitivity and resolution of laser induced phenomena with high power delivery.

FEATURES

- Multi Technique platform for TIVA, LIVA, OBIC, SCOBIC, ORBIRCH, RIL, SDL, TBIP
- Standard Dual Laser System – 1064nm and 1340nm
- High power delivery at DUT
- High Resolution Real Time Backside Navigation
- High resolution objectives with Macro Lens
- High resolution stage – 0.1um
- Laser Power Attenuation
- Integratable with any probe station
- Tester Docked Systems - Current systems in the field used for Soft Defects Localization
- PEM on the same platform – SiCCD, InGaAs or HgCdTe detectors



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